



[Handwritten signature]

Docket No.: 4358-0116P
(PATENT)

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of:
Hai-Wen CHEN et al.

Application No.: 10/727,039

Confirmation No.: 4864

Filed: December 4, 2003

Art Unit: 2625

For: SYSTEM AND METHOD FOR ESTIMATING
NOISE USING MEASUREMENT BASED
PARAMETRIC FITTING NON-UNIFORMITY
CORRECTION

Examiner: Y. J. Couso

STATUS INQUIRY

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

It is respectfully requested that the attorney named below be advised of the status of the above-identified application. Please advise us of when we might expect to receive an Office Action from the Patent and Trademark Office.

Dated:

NOV 4 2005

Respectfully submitted,

By *[Signature]* #39491
+ Michael K. Mutter
Registration No.: 29,680
BIRCH, STEWART, KOLASCH & BIRCH, LLP
8110 Gatehouse Road
Suite 100 East
P.O. Box 747
Falls Church, Virginia 22040-0747
(703) 205-8000
Attorney for Applicant